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16	0	385/37.ccls. and (echelle with ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:09
17	16	385/37.ccls. and (echelle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:09
18	0	(echelle near3 grating near5 ellipt\$5) with facet	USPAT; EPO; JPO; DERWENT	2003/06/18 18:10
19	0	(echelle near3 grating near5 ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:10
20	0	(echelle near grating with ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
21	0	(echelle near grating) with ellipt\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
22	184	(echelle near grating)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
23	23	(echelle near grating).ti.	USPAT; EPO; JPO; DERWENT	2003/06/18 18:12
24	0	(echelle near grating) with definition	USPAT; EPO; JPO; DERWENT	2003/06/18 18:12
25	0	(echelle near grating) with defin\$1	USPAT; EPO; JPO; DERWENT	2003/06/18 18:13
26	6	(echelle near3 grating) with defin\$3	USPAT; EPO; JPO; DERWENT	2003/06/18 18:13
27	6	(echelle near3 grating) with defin\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:14
28	1	(echelle near3 grating) with astigmat\$4	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
29	15	(echelle near3 grating) with fac\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:42
30	2	("4205229" "5018856").PN.	USPAT	2003/06/18 18:22
31	3	6078048.URPN.	USPAT	2003/06/18 18:23
32	2	6067197.URPN.	USPAT	2003/06/18 18:23
33	10	(echelle near3 grating) and (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:54
34	0	(echelle near3 grating) near7 (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:55
35	0	(echelle near3 grating) with (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
36	1	("20020131708").PN.	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
37	37	(echelle near grating) with order	USPAT; EPO; JPO; DERWENT	2003/06/18 18:58

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(echelle grating)

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